

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

JC927 U.S. PTO
10/025699
12/26/01

In re application of

Masayuki NAYA

Appln. No. Not yet assigned

Confirmation No.: Not Yet Assigned

Group Art Unit: Not Yet Assigned

Filed: December 26, 2001

Examiner: Not Yet Assigned

For: SENSOR DETECTING ATTENUATED TOTAL REFLECTION ANGLE BY USING
SEMICONDUCTOR LASER UNIT DRIVEN WITH DRIVING CURRENT ON WHICH
HIGH FREQUENCY COMPONENT IS SUPERIMPOSED

INFORMATION DISCLOSURE STATEMENT
UNDER 37 C.F.R. §§ 1.97 and 1.98

Commissioner for Patents
Washington, D.C. 20231

Sir:

In accordance with the duty of disclosure under 37 C.F.R. § 1.56, Applicant hereby notifies the U.S. Patent and Trademark Office of the documents which are listed on the attached Form PTO-1449 and/or listed herein and which the Examiner may deem material to patentability of the claims of the above-identified application.

One copy of each of the listed documents is submitted herewith.

The present Information Disclosure Statement is being filed: (1) No later than three months from the application's filing date for an application other than a continued prosecution application (CPA) under § 1.53(d); (2) Before the mailing date of the first Office Action on the merits (whichever is later); or (3) Before the mailing date of the first Office Action after filing a

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14Feb02
R. Talbot

INFORMATION DISCLOSURE STATEMENT
Attorney Docket. No. Q66570

request for continued examination (RCE) under §1.114, and therefore, no Statement under 37 C.F.R. § 1.97(e) or fee under 37 C.F.R. § 1.17(p) is required.

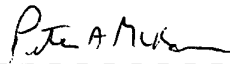

In compliance with the concise explanation requirement under 37 C.F.R. § 1.98(a)(3) for foreign language documents, Applicant submits the following explanations:

Japanese Unexamined Patent Publication No. 6(1994)-167443 is disclosed on page 2 in the specification of the above-identified application. Additionally, English Language Abstract JP 6167443 is submitted herewith.

The submission of the listed documents is not intended as an admission that any such document constitutes prior art against the claims of the present application. Applicant does not waive any right to take any action that would be appropriate to antedate or otherwise remove any listed document as a competent reference against the claims of the present application.

Respectfully submitted,

SUGHRUE MION, PLLC
2100 Pennsylvania Avenue, N.W.
Washington, D.C. 20037-3213
Telephone: (202) 293-7060
Facsimile: (202) 293-7860

 *Reg. No. 38,551*
Darryl Mexic
 Registration No. 23,063

Date: December 26, 2001
DM/mrl

Substitute for form 1449 A & B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				<i>Complete if Known</i>	
				Application Number	Not yet assigned
				Confirmation Number	Not Yet Assigned
				Filing Date	December 26, 2001
				First Named Inventor	Masayuki NAYA
				Art Unit	Not Yet Assigned
				Examiner Name	Not Yet Assigned
Sheet	1	of	1	Attorney Docket Number	Q66570

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U.S. PAT. & T.M. OFFICE

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁶
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			
		JP	6-167443		6/14/94		

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
		Surface Refracto-Sensor Using Evanescent Waves Principles and Instrumentations, Takayuki Okamoto, Optical Engineering Laboratory, The Institute of Physical and Chemical Research (RIKEN) (Received December 8, 1997), "Spectral Researches" / Vol. 47, November 1, 1998	

Examiner Signature		Date Considered	
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²See Kinds Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to indicate here if English language Translation is attached.